

Notice of References Cited	Application/Control No. 10/526,031	Applicant(s)/Patent Under Reexamination MIYASAKA ET AL.	
	Examiner Elias Desta	Art Unit 2857	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,484,109	11-2002	Lofall, Dean A.	702/56
*	B	US-2002/0083779	07-2002	Narita et al.	73/862.191
*	C	US-6,199,018	03-2001	Quist et al.	702/34
*	D	US-2005/0259903	11-2005	Takizawa et al.	384/448
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	ULB SMA, 'A Lab View mini-expert to identify bearing defects automatically', 1999, ULB Web Publication, pages 1-21
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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